

# 25V N-Channel Trench MOSFET

## **FEATURES**

- Super Low Gate Charge
- 100% EAS Guaranteed
- RoHS compliant
- Green Device Available
- Excellent CdV/dt effect decline
- Advanced high cell density Trench technology

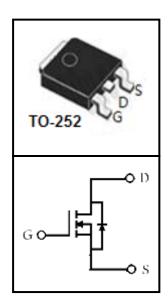
### **APPLICATIONS**

- Load Switching
- Power Motor Controls
- High Frequency Isolated DC-DC Converters with

Synchronous Rectification for Industrial

Device Marking and Package Information				
Device	Package	Marking		
CTD02N004	TO-252	CTD02N004		





<b>Absolute Maximum Ratings</b> at $T_j$ = 25°C unless otherwise noted				
Parameter		Symbol	Value	Unit
Drain-Source Voltage (V <sub>GS</sub> = 0V)		$V_{DSS}$	25	V
Continuous Drain Current T <sub>C</sub> = 25°C	(note1)		90	А
Continuous Drain Current T <sub>C</sub> = 100°C	(note1)	I <sub>D</sub>	65	A
Pulsed Drain Current	(note2)	I <sub>DM</sub>	340	А
Gate Source Voltage		$V_{GSS}$	±12	V
Single Pulse Avalanche Energy	(note3)	E <sub>AS</sub>	340	mJ
Power Dissipation $T_C = 25^{\circ}C$	(note4)	$P_{D}$	87	W
Operating Junction and Storage Temperature Range		$T_J$ , $T_{stg}$	-55~+175	°C

Thermal Characteristics				
Parameter		Symbol	Value	Unit
Thermal Resistance, Junction-Case	(note1)	$R_{ heta JC}$	1.72	°C/W

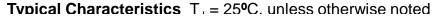


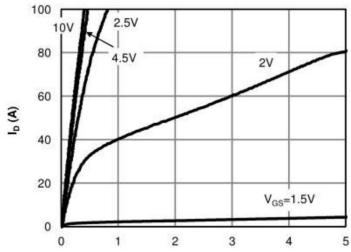
Electrical Characteristics T <sub>j</sub> = 25°C unless otherwise specified								
Doromotor	Completed	Total Octobries	Value			11.24		
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit		
Static								
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	25			V		
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{DS} = 20V, V_{GS} = 0V, T_{J} = 25^{\circ}C$			1	uA		
Zoro Gato Voltago Brain Garront	טאטי	$V_{DS} = 20V, V_{GS} = 0V, T_{J} = 100^{\circ}C$			5	uA		
Gate-Source Leakage	$I_{GSS}$	$V_{GS} = \pm 12V$			±100	nA		
Gate-Source Threshold Voltage	$V_{\text{GS(th)}}$	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	0.4	0.75	1.2	V		
		$V_{GS} = 10V, I_D = 30A$		3.1	4	mΩ		
Drain-Source On-Resistance (note2)	R <sub>DS(on)</sub>	$V_{GS} = 4.5V, I_{D} = 20A$		3.3	4.5	mΩ		
		$V_{GS} = 2.5V, I_D = 15A$		5.5	8	mΩ		
	Dynamic							
Input Capacitance	$C_{iss}$	$V_{GS} = 0V,$ $V_{DS} = 15V,$		2813		pF nC		
Output Capacitance	$C_{oss}$			355				
Reverse Transfer Capacitance	$C_{rss}$	f = 1.0MHz		263				
Total Gate Charge (4.5V)	$Q_g$			33				
Gate-Source Charge	$Q_{gs}$	$V_{DD} = 10V, I_{D} = 12A,$ $V_{GS} = 4.5V$		4				
Gate-Drain Charge	$Q_gd$			14				
Turn-on Delay Time	$t_{d(on)}$			18		ns		
Turn-on Rise Time	t <sub>r</sub>	$V_{DS} = 15V, R_{L} = 0.75\Omega,$		53				
Turn-off Delay Time	$t_{\text{d(off)}}$	$V_{GS} = 4.5V, R_G = 3\Omega$		76				
Turn-off Fall Time	t <sub>f</sub>			28				
Body Diode Characteristics								
Continuous Body Diode Current	Is	T <sub>C</sub> = 25 °C			90	А		
Body Diode Voltage	$V_{SD}$	$T_J = 25^{\circ}\text{C}, I_{SD} = 5\text{A}, V_{GS} = 0\text{V}$			1.2	V		
Reverse Recovery Time	t <sub>rr</sub>	TJ=25°C I <sub>F</sub> =30A,		25		nS		
Reverse Recovery Charge	Q <sub>rr</sub>	di/dt=100A/μs		13		nC		

#### **Notes**

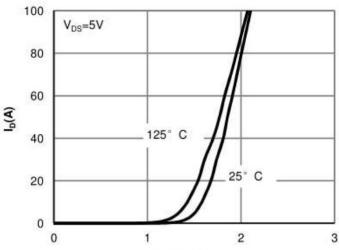
- 1. The data tested by surface mounted on a 1 inch2 FR-4 board with 2OZ copper.
- 2. The data tested by pulsed , pulse width≦300us , duty cycle≦2%
- 3. The EAS data shows Max. rating . The test condition is VDD =25V,VGS =10V,L=0.1mH  $\,$
- 4. The power dissipation is limited by 175°C junction temperature
- 5. The data is theoretically the same as ID and IDM, in real applications, should be limited by total power dissipation.



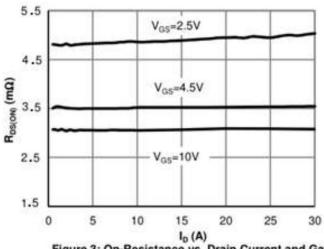




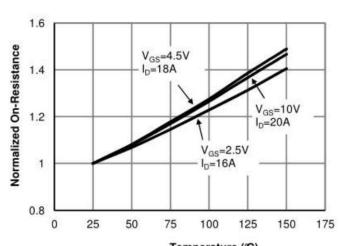
V<sub>DS</sub> (Volts) Fig 1: On-Region Characteristics (Note E)



V<sub>GS</sub>(Volts)
Figure 2: Transfer Characteristics (Note E)



I<sub>0</sub> (A)
Figure 3: On-Resistance vs. Drain Current and Gate
Voltage (Note E)



Temperature (°C)
Figure 4: On-Resistance vs. Junction Temperature
(Note E)

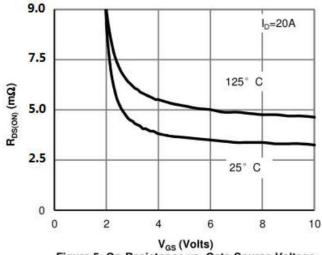
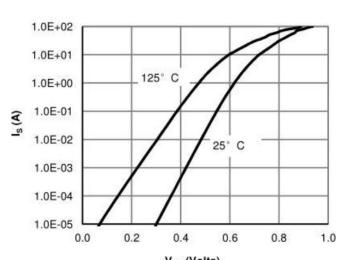


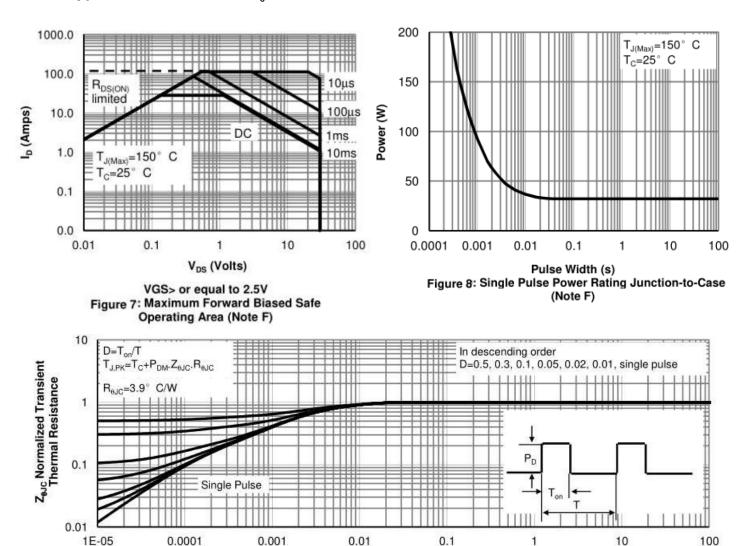
Figure 5: On-Resistance vs. Gate-Source Voltage
(Note E)



V<sub>SD</sub> (Volts) Figure 6: Body-Diode Characteristics (Note E)



## **Typical Characteristics** $T_J = 25$ °C, unless otherwise noted



Pulse Width (s)
Figure 9: Normalized Maximum Transient Thermal Impedance (Note F)



Figure A: Gate Charge Test Circuit and Waveform

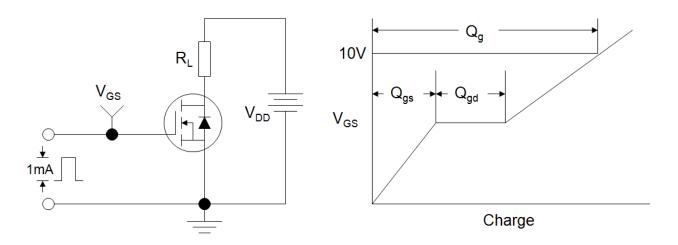


Figure B: Resistive Switching Test Circuit and Waveform

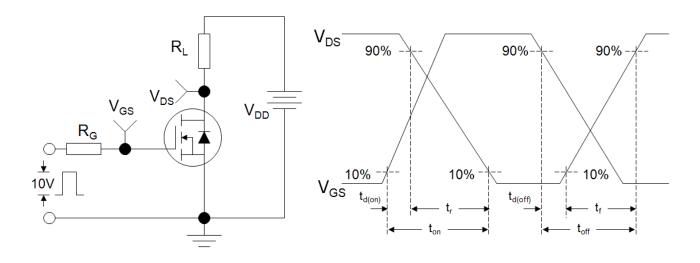
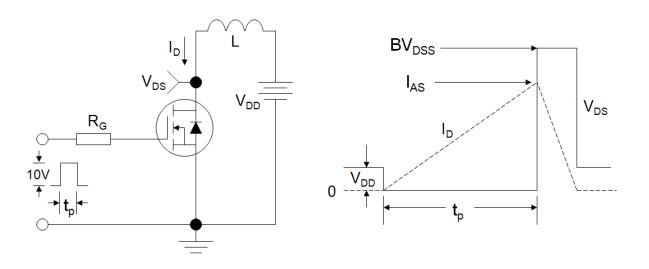
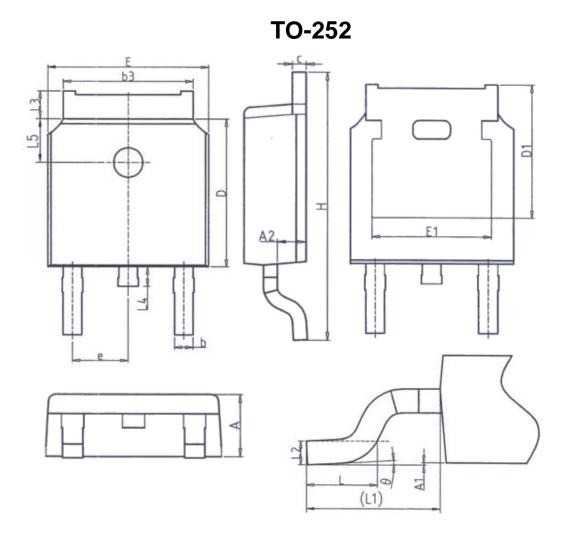


Figure C: Unclamped Inductive Switching Test Circuit and Waveform







Unit: mm			
Symbol	Min.	Max.	
Α	2. 20	2. 40	
A1	0.00	0. 20	
A2	0. 97	1. 17	
b	0. 68	0.90	
b3	5. 20	5. 50	
С	0. 43	0. 63	
D	5. 98	6. 22	
D1	5. 30REF		
E	6. 40	6. 80	
E1	4. 63	_	

Unit: mm				
Symbol	Min. Max.			
е	2. 286BSC			
Н	9. 40	10.50		
L	1. 38	1. 75		
L1	2. 90REF			
L2	0. 51BSC			
L3	0.88	1. 28		
L4	_	1.00		
L5	1. 65	1. 95		
θ	0°	8°		



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